



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 09/814,260
Filing Date March 21, 2001
Inventor Scott E. Moore et al.
Assignee Micron Technology, Inc.
Group Art Unit 3723
Examiner T. Eley
Attorney's Docket No. MI22-1663
Title: "Semiconductor Workpiece Processing Methods, A Method of Preparing
Semiconductor Workpiece Process Fluid, and A Method of Delivering
Semiconductor Workpiece Process Fluid to a Semiconductor Processor"

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No
admission is made regarding whether all the submitted references are prior art.

Respectfully submitted,

Dated: 11/12/04

Attorney:

James D. Shaurette
Reg. No. 39,833

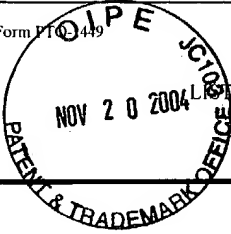
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| Form PTO 449  | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY. DOCKET NO. M122-1663 | | SERIAL NO. 09/814,260 | |
| LITERATURE OF ART CITED BY APPLICANT (Use several sheets if necessary) | | | | APPLICANT Scott E. Moore et al. | | | |
| FILING DATE March 21, 2001 | | | | GROUP 3723 | | | |

| U.S. PATENT DOCUMENTS | | | | | | | |
|-----------------------|-----------------|-----------|-----------|--------------|----------|----------------------------|--|
| *Examiner Initial | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate | |
| | AA | 5,446,531 | 8/29/1995 | Boyer et al. | | | |
| | AB | 4,730,922 | 3/15/1988 | Bach et al. | | | |
| | AC | | | | | | |
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| FOREIGN PATENT DOCUMENTS | | | | | | | |
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| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) | |
|-------------------------------------------------------------------------|-----------------|
| EXAMINER | DATE CONSIDERED |

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.